



LUND
UNIVERSITY

EITF35: Introduction to Structured VLSI Design

Part 4.2.1: Learn More ...

Liang Liu
liang.liu@eit.lth.se



Outline

□ Crossing clock domain

□ Reset, synchronous or asynchronous?



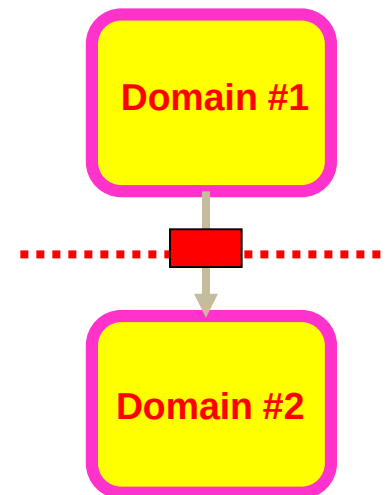
□ Why two DFFs?



Crossing clock domain

❑ Multiple clock is needed in case:

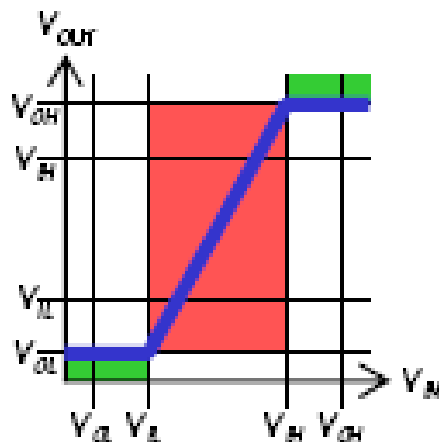
- Inherent system requirement
 - ❑ *Different clocks for sampling and processing*
- Chip size limitation
 - ❑ *Clock skew increases with the # FFs in a system*



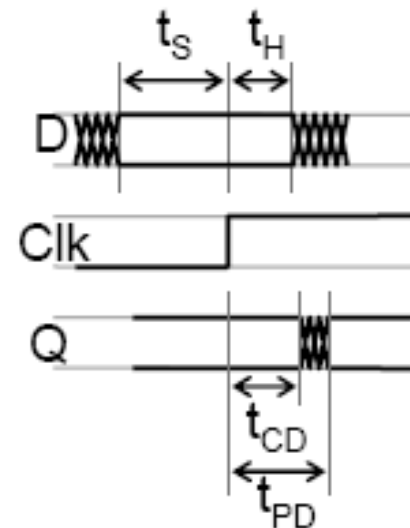
Multiple Clocks: Problems

□ We have been setting very strict rules to make our digital circuits safe: using a forbidden zone in both voltage and time dimensions

Digital Values: distinguishing voltages representing “1” from “0”



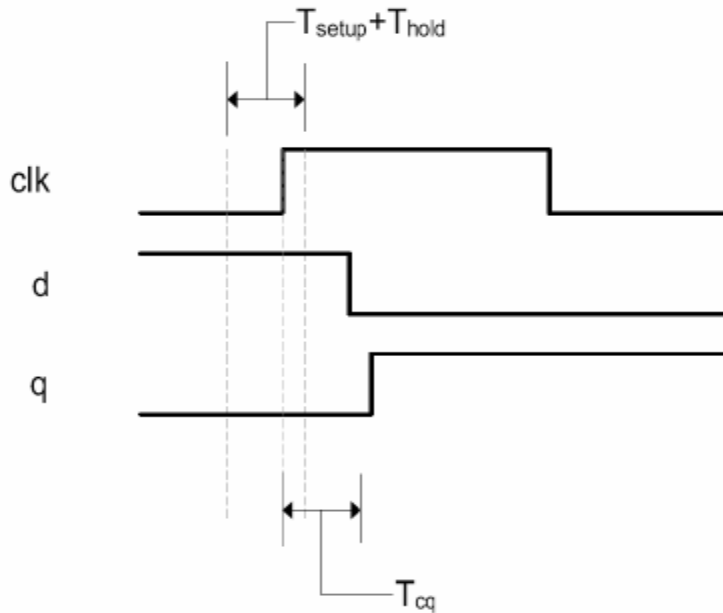
Digital Time: setup and hold time rules



Metastability

□ With asynchronous inputs, we have to break the rules: *we cannot guarantee that setup and hold time requirements are met at the inputs!*

□ What happens after timing violation?



clk

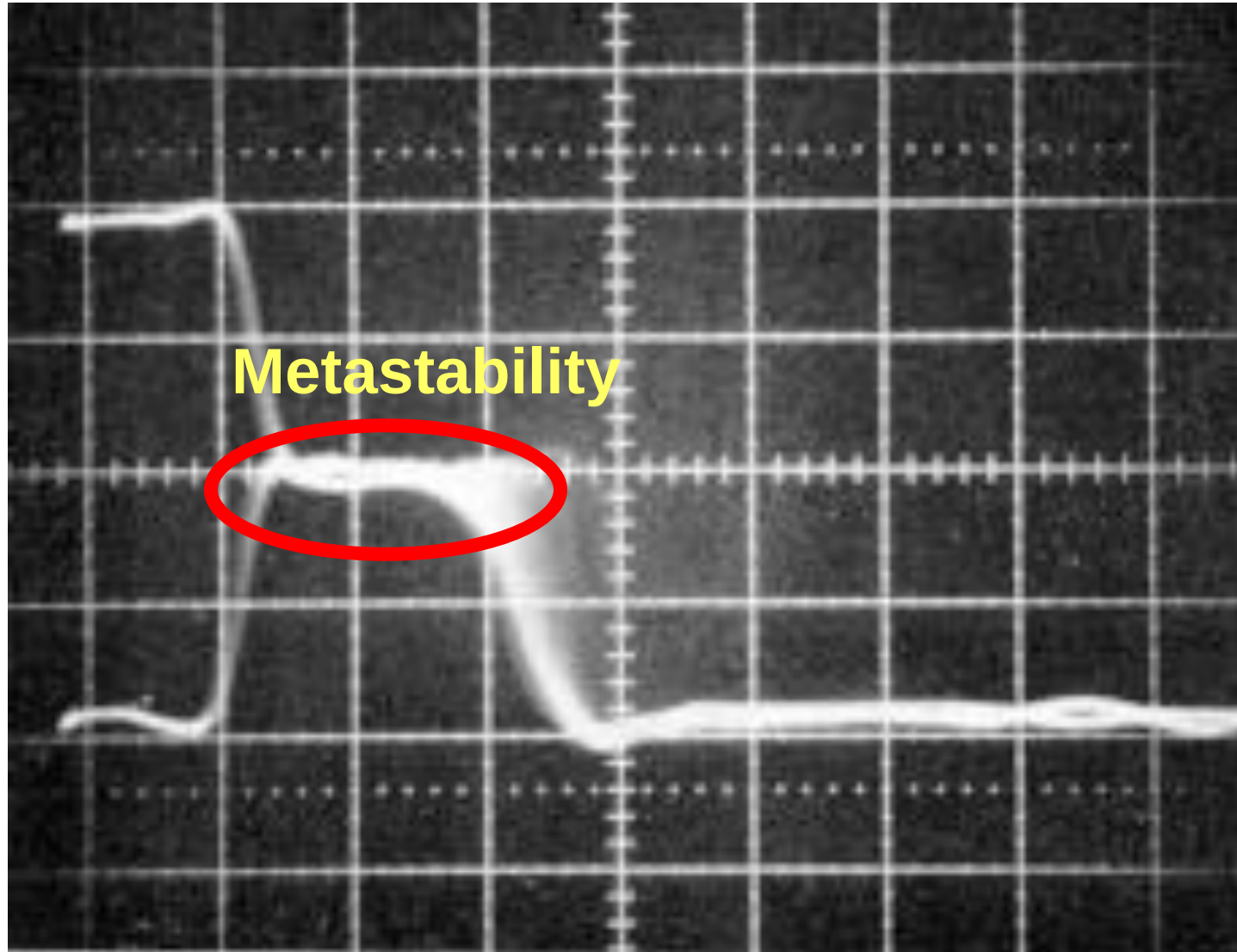
setup hold

D

Q



Metastability in Digital Logic

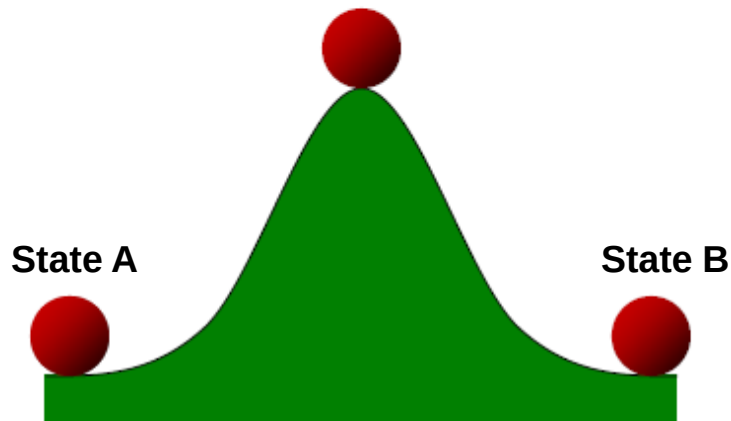


Mechanical Metastability



□ Launch a golf up a hill, 3 possible outcomes:

- Hit lightly: Rolls back
- Hit hard: Goes over
- Or: Stalls at the apex



□ That last outcome is not stable:

- A gust of wind
- Brownian motion
- *Can you tell the eventual state?*

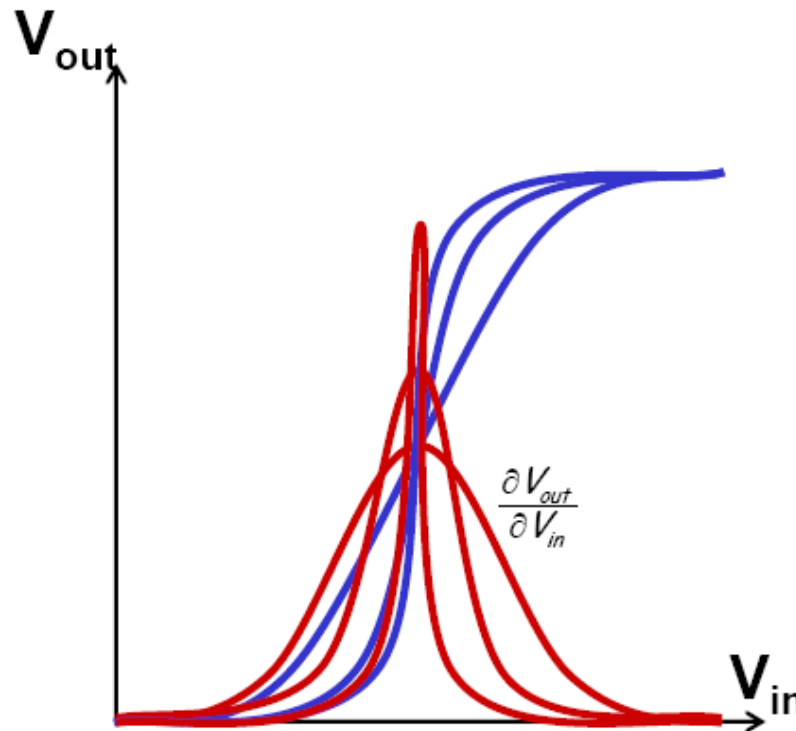


Metastability in Digital Logic

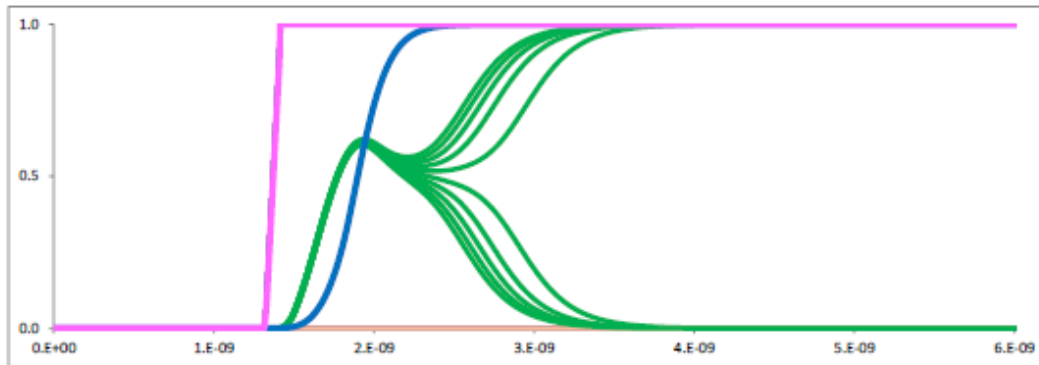
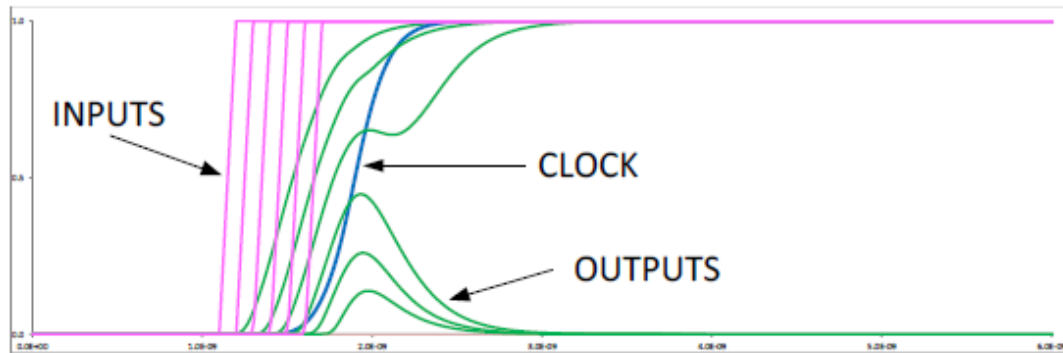
□ Our hill is related to the VTC (Voltage Transfer Curve).

- The higher the gain thru the transition region
- The steeper the peak of the hill
- The harder to get into a metastable state.

□ We can decrease the probability of getting into the metastable state, but we can't eliminate it...



Metastability in Digital Logic



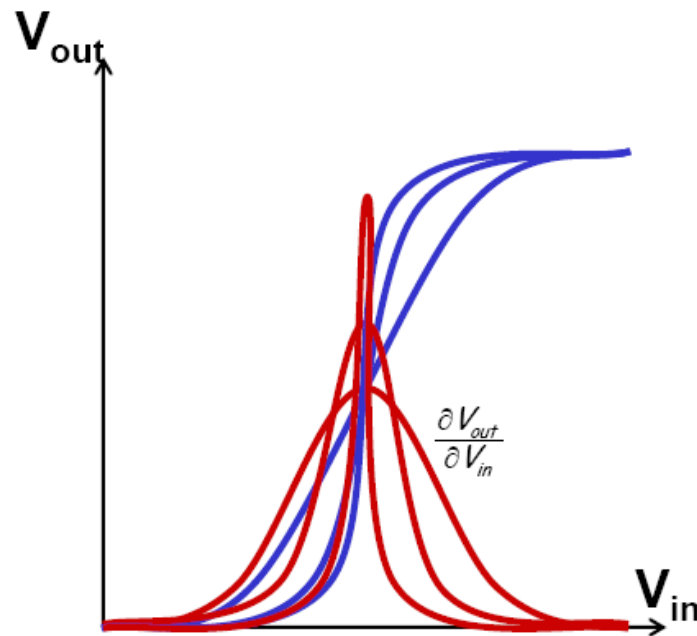
- ❑ Fixed clock edge
- ❑ Change the edge of inputs
- ❑ The input edge is moved in steps of 100ps and 1ps
- ❑ The behavior of outputs
 - 'Three' possible states
 - Will exit metastability

How long it takes to exit Metastability?



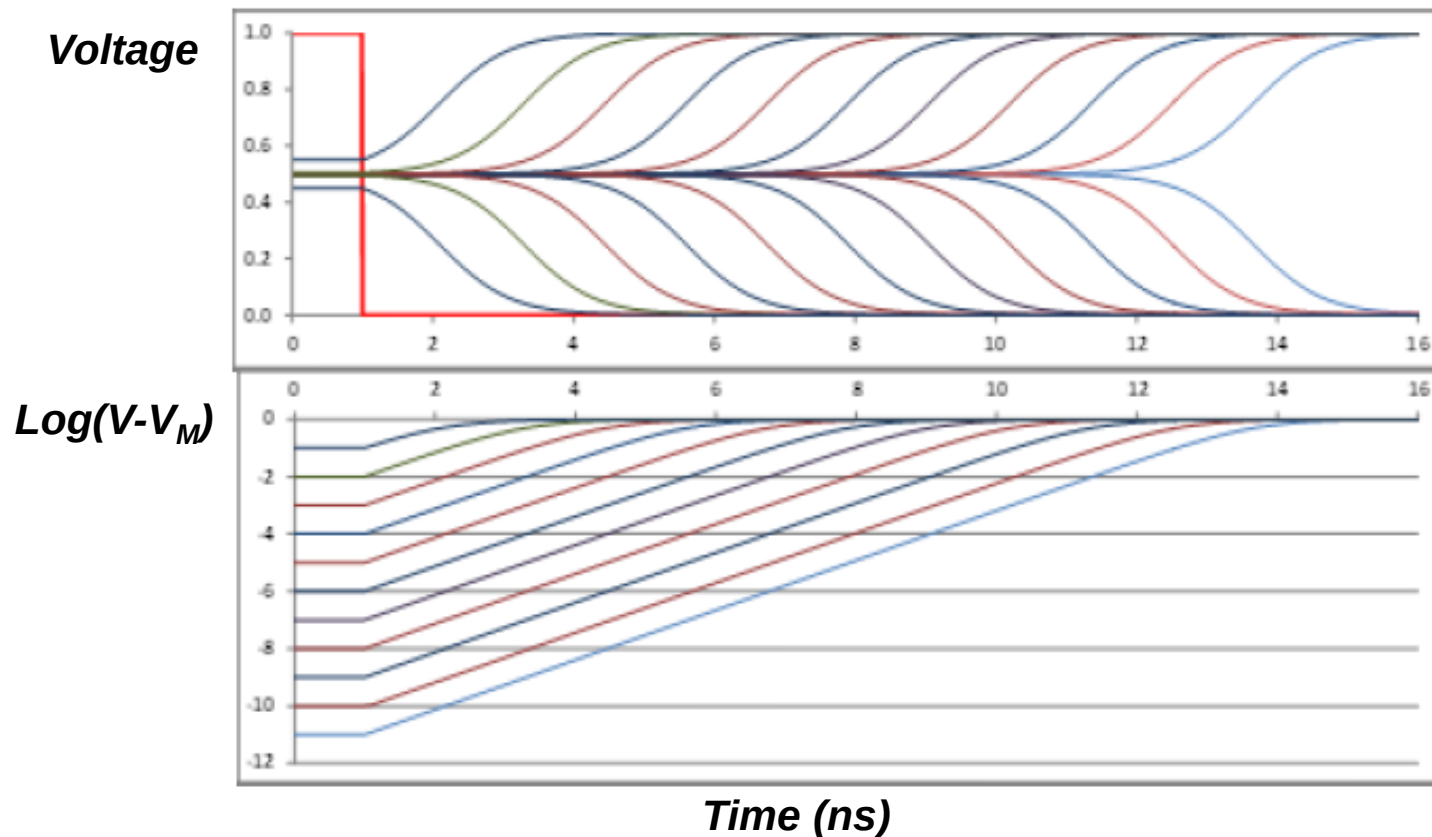
Exit Metastability

- Define a fixed-point voltage, V_M , (always have) such that $V_{IN} = V_M$ implies $V_{OUT} = V_M$
- Assume the device is sampling at some voltage V_0 near V_M
- The time to settle to a stable value depends on $(V_0 - V_M)$; its theoretically infinite for $V_0 = V_M$



Exit Metastability

- The time to exit metastability depends *logarithmically on $(V_0 - V_M)$*
- The *probability* of remaining metastable at time **T** is $e^{-T/\tau}$



MTBF: The probability of being metastable at time S ?

□ Two conditions have to be met concurrently

- An FF enters the metastable state
- An FF cannot resolve the metastable condition within S

□ The rate of failure $p(\text{failure}) = p(\text{enter MS}) \times p(\text{time to exit} > S)$

$$\text{Rate}(\text{failures}) = T_W F_C F_D \times e^{-S/\tau}$$

- T_W : time window around sampling edge incurring metastability
- F_C : clock rate (assuming data change is uniformly distributed)
- F_D : input change rate (input may not change every cycle)

□ Mean time between failures (MTBF)

$$\text{MTBF} = \frac{e^{S/\tau}}{T_W F_C F_D}$$



MTBF (Mean Time Between Failure)

□ Let's calculate an ASIC for 28nm CMOS process

- τ : 10ps (different FFs have different τ)
- $T_w=20\text{ps}$, $F_c=1\text{GHz}$
- Data changes every ten clock cycles
- Allow 1 clock cycle to resolve metastability, $S=T_c$

$$\text{MTBF} = 4 \times 10^{29} \text{ year !}$$

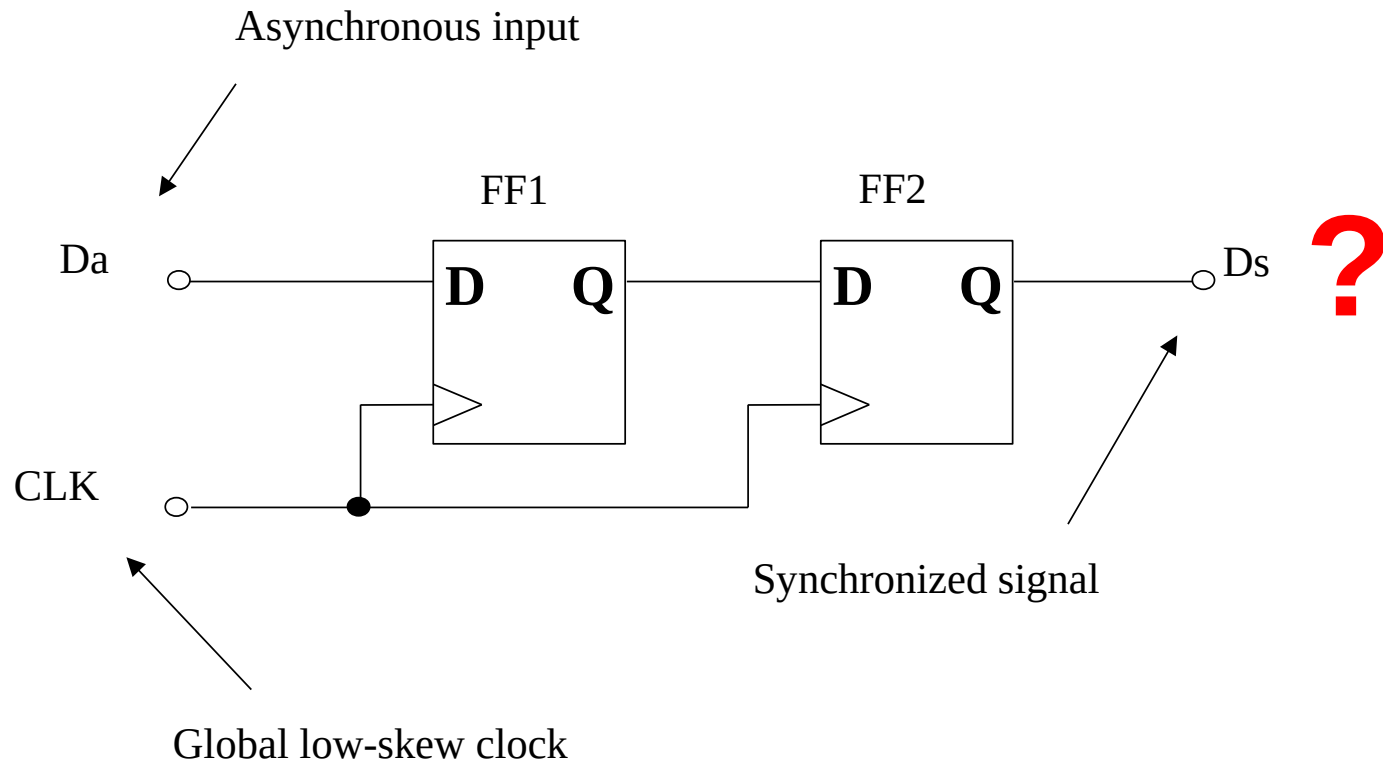
[For comparison:

Age of oldest hominid fossil: 5×10^6 years

Age of earth: 5×10^9 years]



The Two-Flip-Flop Synchronizer

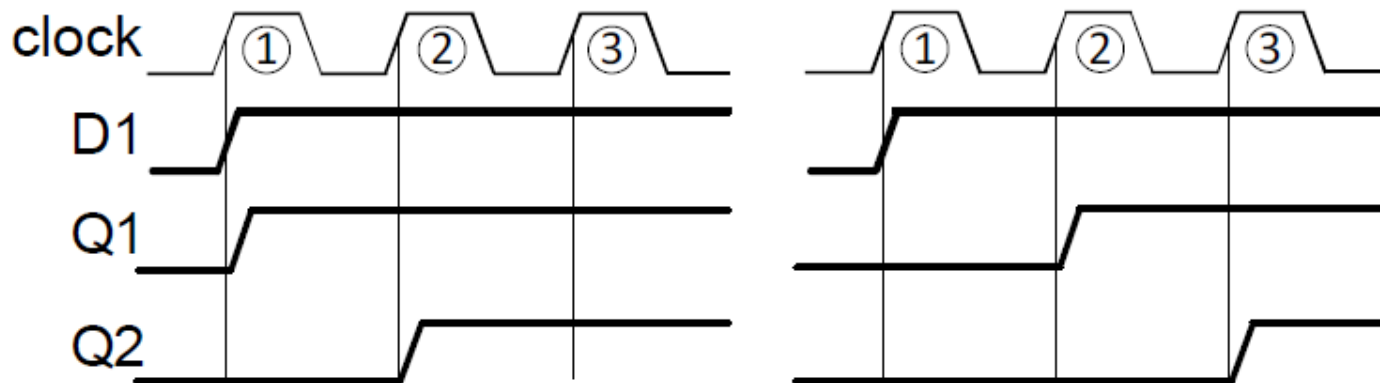
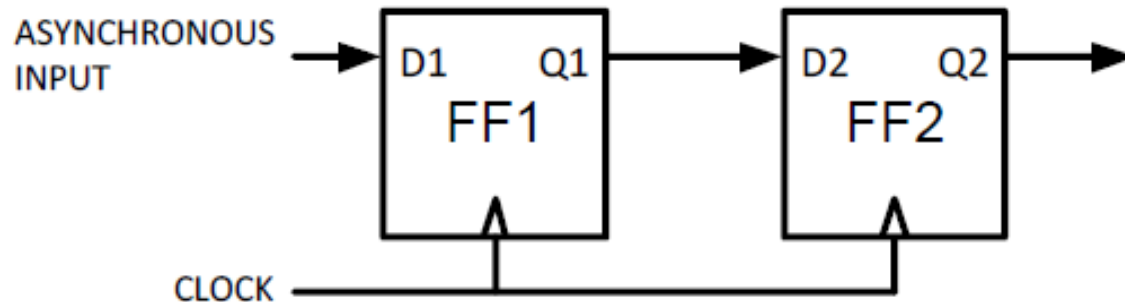


$$S = T_c$$



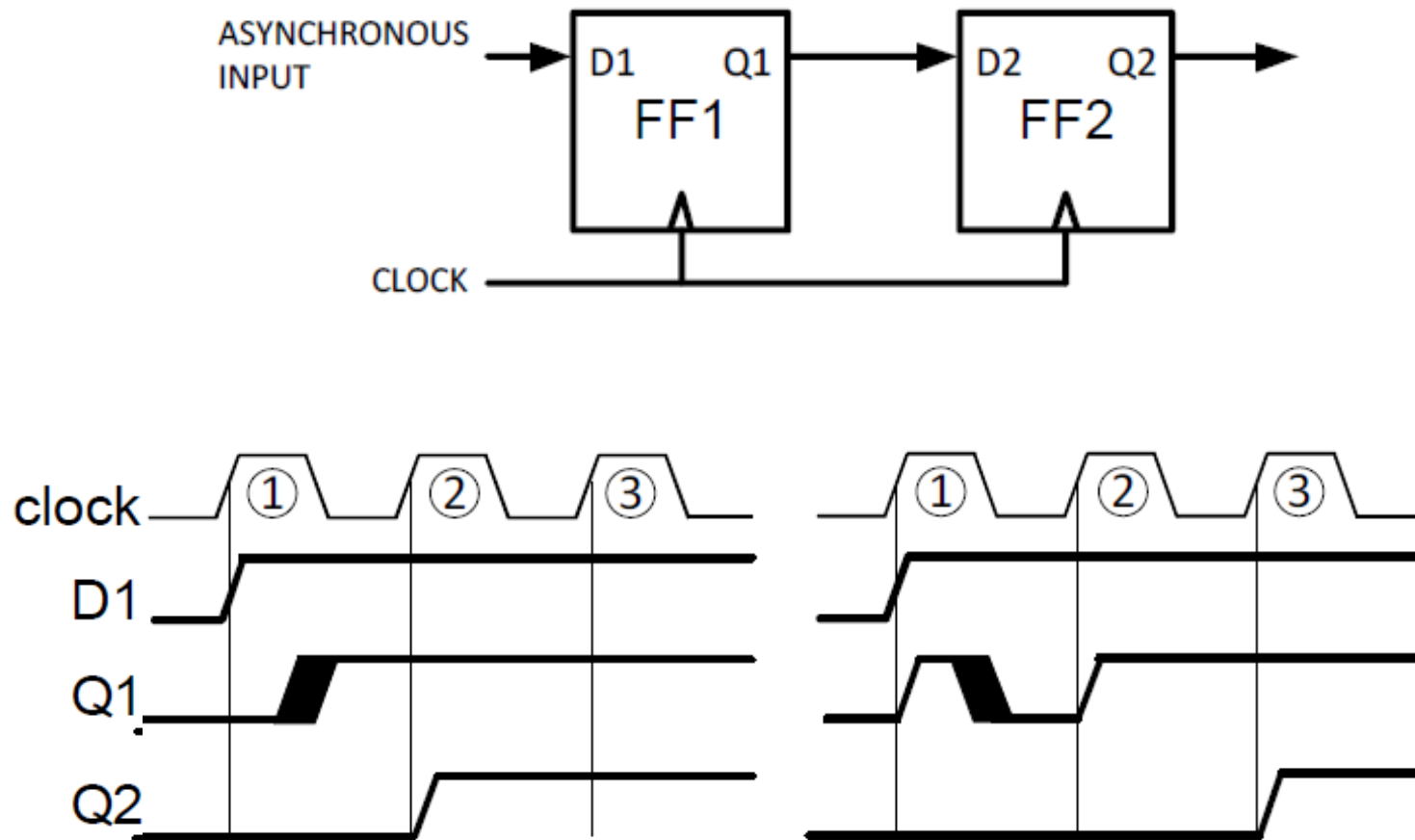
The Two-Flip-Flop Synchronizer

Possible Outcomes



The Two-Flip-Flop Synchronizer

Possible Outcomes



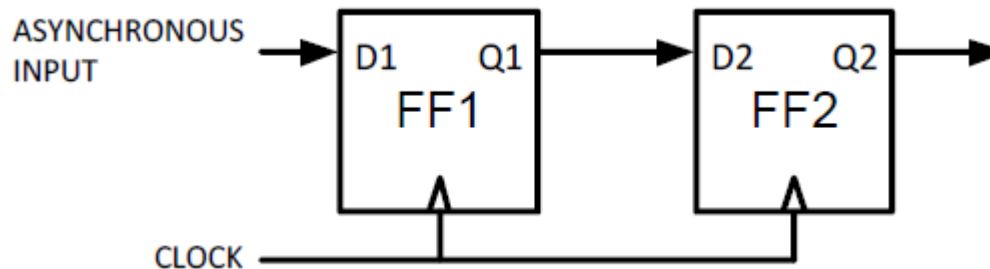
Open Question: What is the limitation?



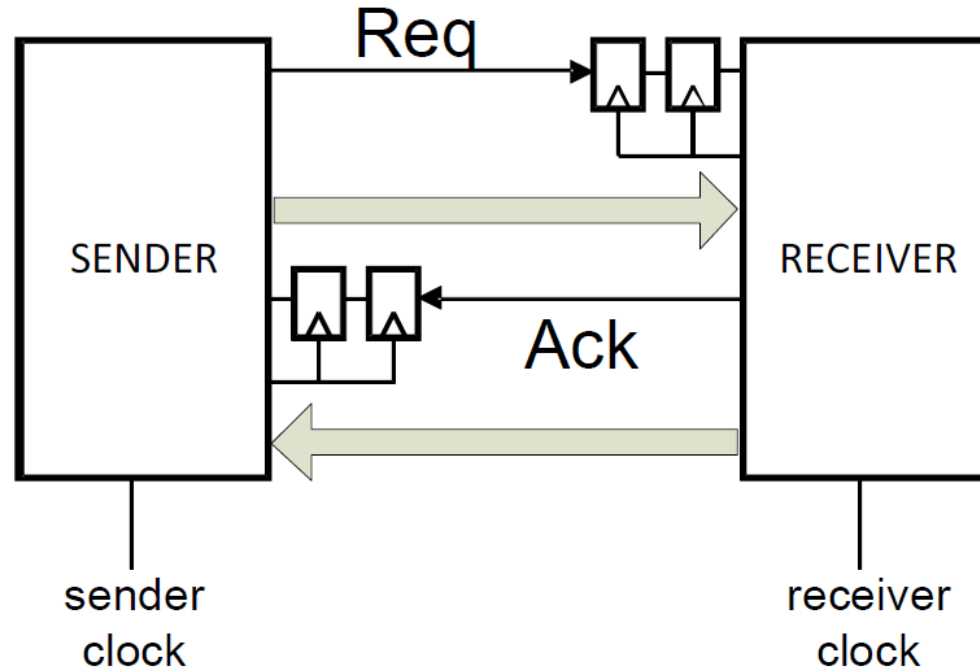
The Two-Flip-Flop Synchronizer

□ Problems

- Just ensures that the receiving system does not enter a metastable state
- Not guarantee the **“function”** of the received signal
 - **Uncertainty Remains: Q2 goes high either *one or two* cycles later than the input**
- D1 must stay high for at *least two cycles*.
- How about data bus (**multiple bits**) crossing clock domain?
 - **Some bits may pass through the synchronizer after one cycle while others may take two cycles.**



A Complete Synchronizer



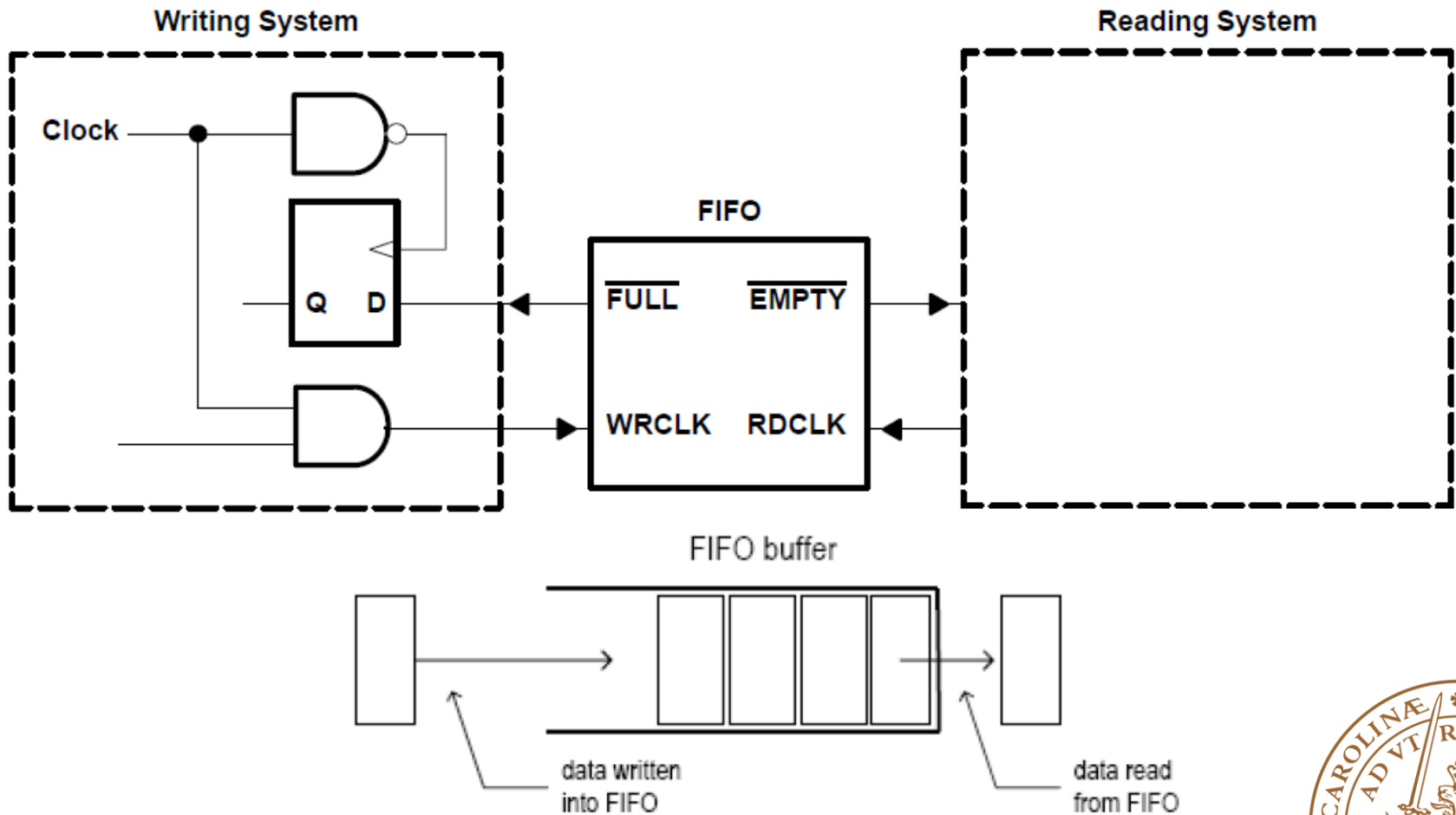
- ❑ The sender place data on the bus
- ❑ The sender sends Req, Req gets synchronized by the top synchronization circuits
- ❑ The receiver gets data and sends back ACK
- ❑ Ack gets synchronized by the sender, and only then is the sender allowed to start a new cycle again.



FIFO

□ FIFO (first in first out) Buffer

- “Elastic” storage between two subsystems



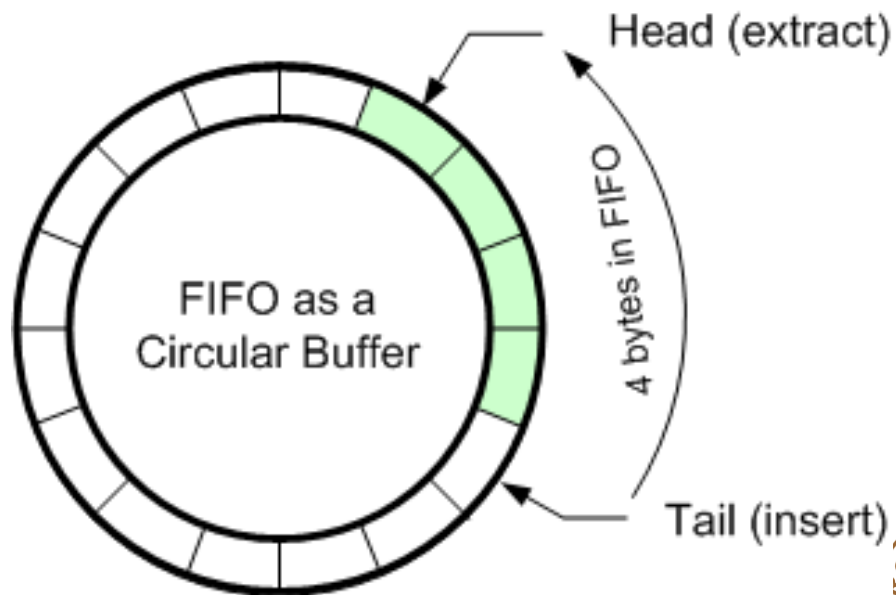
Circular FIFO

□ How to Implement a FIFO?

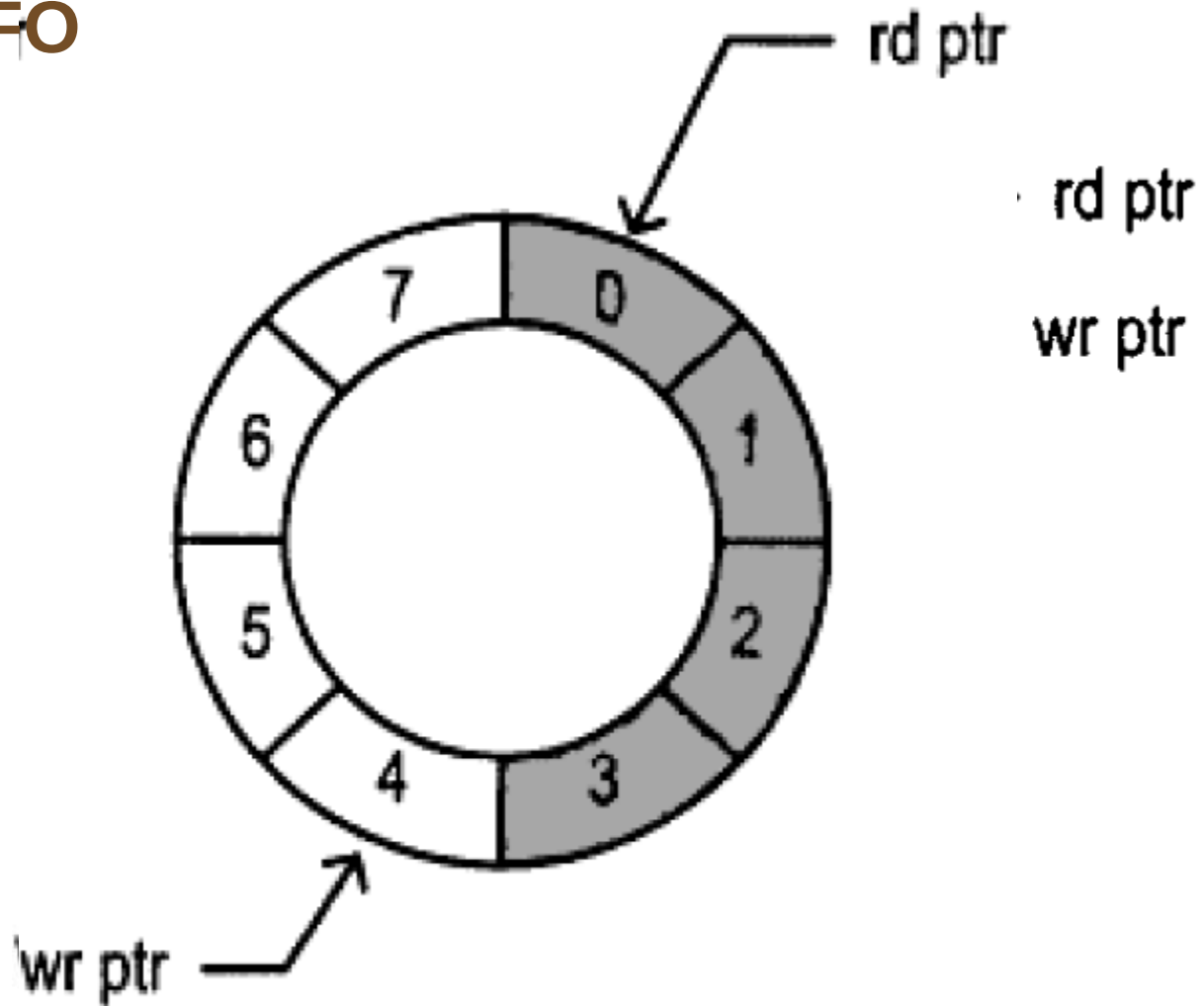
- Circular queue implementation
- Use two pointers and a “generic storage”
 - **Write pointer:** point to the empty slot before the **head** of the queue
 - **Read pointer:** point to the **tail** of the queue



"First in? First out!"



Circular FIFO



(c). 4 more writes



FIFO Implementation

Overall Architecture

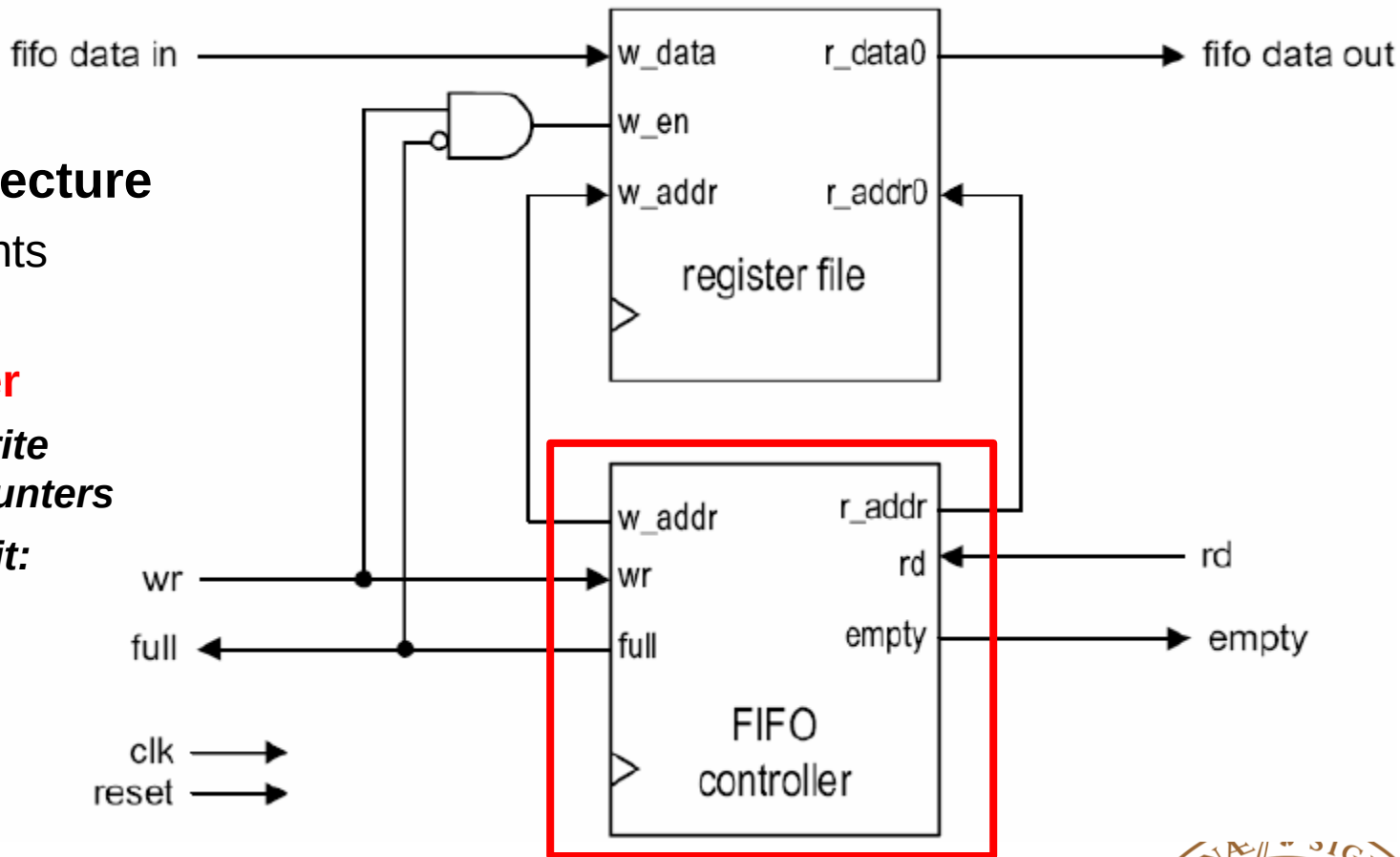
- Storage Elements

 - Reg. file

- FIFO Controller**

 - Read and write pointers: 2 counters

 - Status circuit:
full, empty



FIFO Implementation: Controller

□ Augmented binary counter:

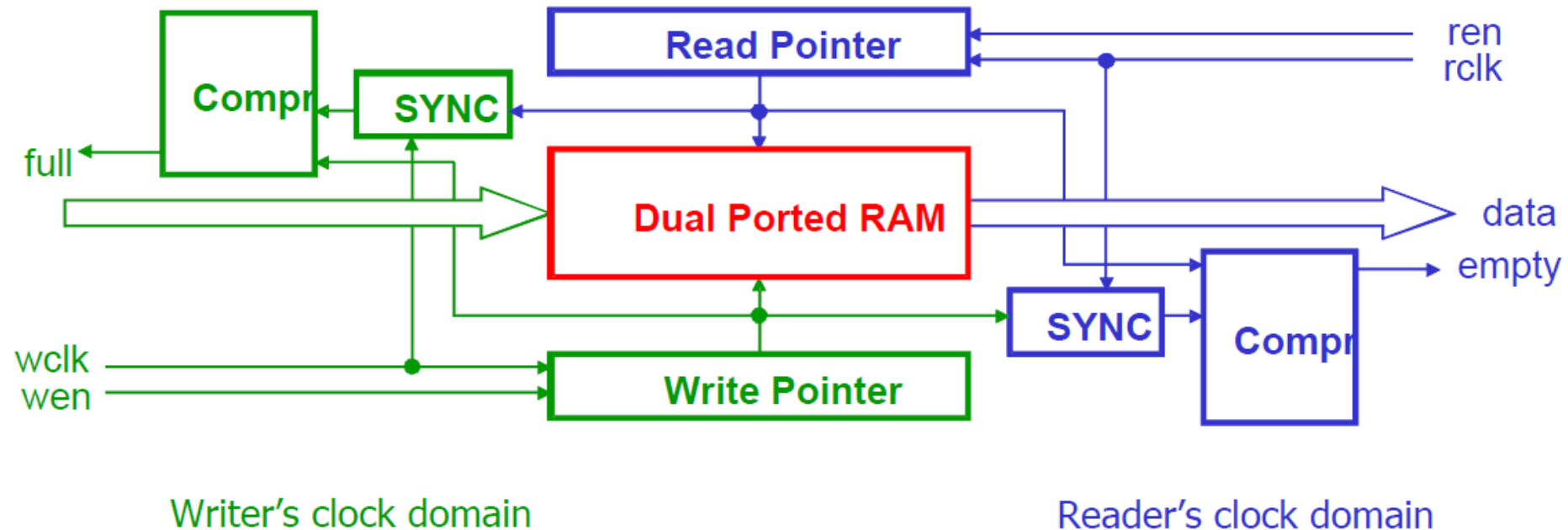
- Increase the counter by 1 bits
- Use LSBs for as register address
- Use **MSB** to distinguish full or empty

Write pointer	Read pointer	Operation	Status
0 000	0 000	initialization	empty
0 111	0 000	after 7 writes	
1 000	0 000	after 1 write	full
1 000	0 100	after 4 reads	
1 100	0 100	after 4 writes	full
1 100	1 011	after 7 reads	
1 100	1 100	after 1 read	empty
0 011	1 100	after 7 writes	
0 100	1 100	after 1 write	full
0 100	0 100	after 8 reads	empty

0000
0001
0011
0010
0110
0111
0101
0100
1100
1101
1111
1110
1010
1011
1001
1000



A Complete Synchronizer



- ❑ **Control signals** are 'synchronized', **data** pass through storage elements
- ❑ Assertion delay, it takes **two clock** cycles for the control signal passing through synchronizer
- ❑ Usually available in libraries
- ❑ The key question, **how large the RAM should be?**
- ❑ "When in doubt, double it"



Lecture

□ Sept. 26th Monday (13.15-15.00)



Design for Test (DFT)

Erik Larsson

Associate Professor

□ Sept. 27th Tuesday (13.15-15.00)



Stefan Lundberg



Lecture

□ Oct. 3th Monday No Lecture

□ Oct. 4th Tuesday (13.15-15.00)

Charlotte Sköld
Sadat Rahman

